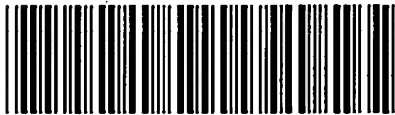


Search Notes



Application/Control No.

10/605,160

Examiner

Rodney G. McDonald

Applicant(s)/Patent under Reexamination

CHIU, WEN-PIN

Art Unit

1753

SEARCHED

Class	Subclass	Date	Examiner
204	192.12	8/10/06	mm
204	192.17	/	/
204	192.15	/	/
204	192.3	8/10/06	mm
204	298.06	/	/
204	298.11	8/10/06	mm

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
See FIRST SEARCH	8/10/06	mm